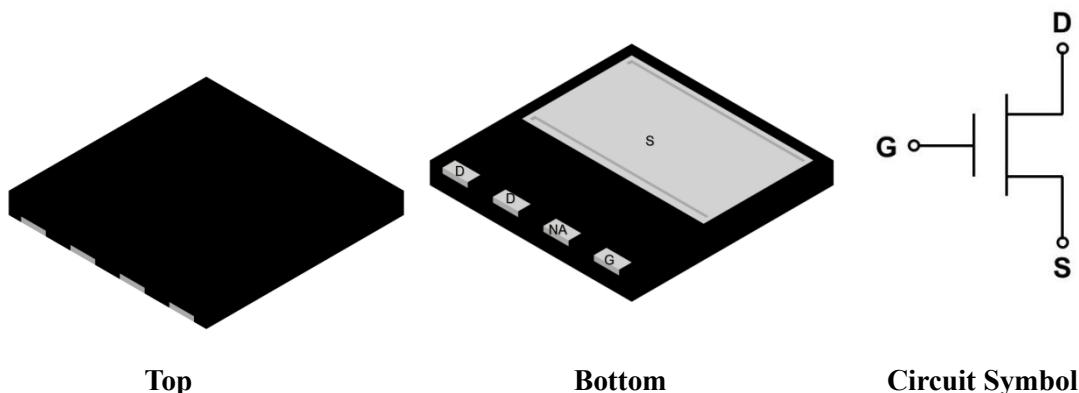


CoreGaN 650V GaN HEMT

Description	General Features
<p>The CE65D150DNBI Series 650V, $150\text{m}\Omega$ gallium nitride (GaN) FETs are normally-on devices. Coreenergy GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and zero reverse recovery charge, delivering significant advantages over traditional silicon (Si) devices.</p> <p>Coreenergy is a leading-edge wide band gap supplier with world-class innovation .</p>	<p>Easy to drive—compatible with standard gate drivers</p> <p>Low conduction and switching losses</p> <p>RoHS compliant and Halogen-free</p>
Application	Benefits
<p>Fast charger</p> <p>Renewable energy</p> <p>Telecom and data-com</p> <p>Servo motors</p> <p>Industrial</p> <p>Automotive</p>	<p>Increased efficiency through fast switching</p> <p>Increased power density</p> <p>Reduced system size and weight</p>
Valid Date: 02/06/2021	

Ordering Information

Part Number	Package	Package Configuration
CE65D150DNBI	PDFN	Source



Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise stated)

Symbol	Parameter	Limit value	Unit
V_{DSS}	Drain to source voltage ($T_J = -55^\circ\text{C}$ to 150°C)	650	V
$V_{(TR)DSS}$	Drain to source voltage-transient ^a	900	
V_{GSS}	Gate to source voltage	-35~+10	

ID	Continuous drain current @ $T_C=25^\circ\text{C}$ ^b		15	A
	Continuous drain current @ $T_C=150^\circ\text{C}$ ^b		10	
IDM	Pulse drain current (pulse width: 100μs)		40	A
P _D	Maximum power dissipation @ $T_C=25^\circ\text{C}$		65	W
T_C	Operating temperature	Case	-55~150	°C
T _J		Junction	-55~150	°C
T _S	Storage temperature		-55~150	°C

Notes:

- a. In off-state, spike duty cycle D<0.01, spike duration <1μs
- b. For increased stability at high current operation

Thermal Resistance

Symbol	Parameter	Limit value			Unit
R _{θJC}	Junction-to-case	1.3			°C /W

Electrical Parameters ($T_J=25^\circ\text{C}$ unless otherwise stated)

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
V _{(BL)DSS}	Drain-source voltage	650	-	-	V	V _{GS} = -25V
V _{GS(th)}	Gate threshold voltage		-18		V	
Δ V _{GS(th)/TJ}	Gate threshold voltage temperature coefficient		-22		mV/°C	V _{DS} =V _{GS} , I _{DS} =1uA
R _{DS(on)}	Drain-source on- resistance	-	150	200	mΩ	V _{GS} =0V, I _D =10A, T _J =25°C
		-	280	-		V _{GS} =0V, I _D =10A, T _J =150°C
I _{DSS}	Drain-to-source leakage current	-	-	0.2	uA	V _{DS} =650V, V _{GS} = -25V, T _J =25°C
		-	-	1		V _{DS} =650V, V _{GS} = -25V, T _J =150°C
I _{GSS}	Gate-to-source forward leakage current	-	-	10	nA	V _{GS} =-25V
C _{iss}	Input capacitance	-	69	-	pF	V _{GS} =-25V, V _{DS} =400V, $f=1\text{MHz}$
C _{oss}	Output capacitance	-	24	-		
C _{rss}	Reverse capacitance	-	7	-		
Q _G	Total gate charge	-	22	-	nC	V _{DS} =400V, V _{GS} =-25V to 0V, I _D =1A
Q _{GS}	Gate-source charge	-	2.4	-		
Q _{GD}	Gate-drain charge	-	15	-		
Q _{oss}	Output charge		22		nC	V _{GS} =-25V, V _{DS} =0V to 400V, $f=1\text{MHz}$
t _{D(on)}	Turn-on delay	-	5	-	ns	V _{DS} =400V, V _{GS} =-25V to 0V, I _D =10A
t _R	Rise time	-	16	-		
t _{D(off)}	Turn-off delay	-	6	-		
t _F	Fall time	-	14	-		

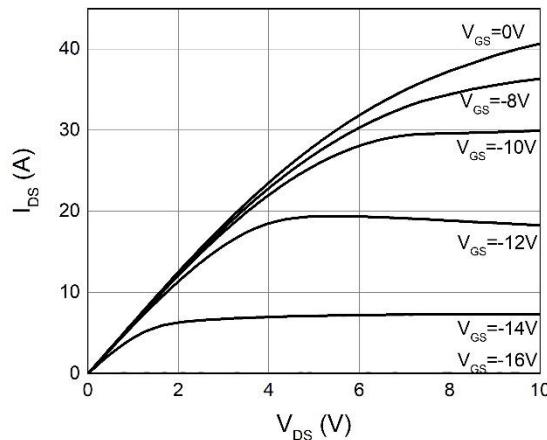
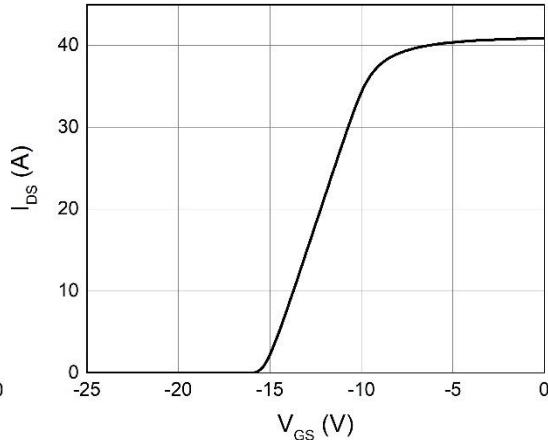
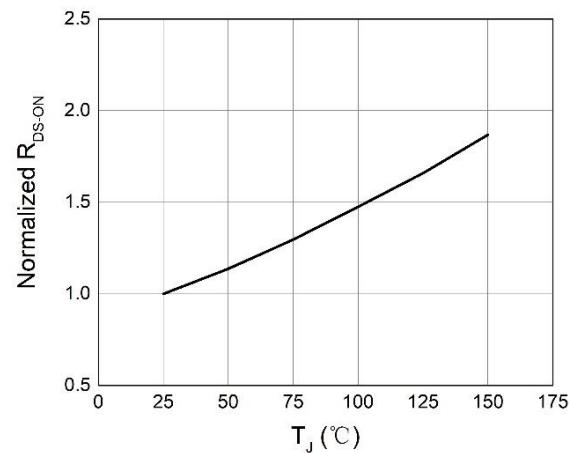
Typical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise stated)
Figure 1. Typical Output Characteristics $T_J=25^\circ\text{C}$ Figure 2. Typical Transfer Characteristics $T_J=25^\circ\text{C}$ 

Figure 3. Normalized On-resistance

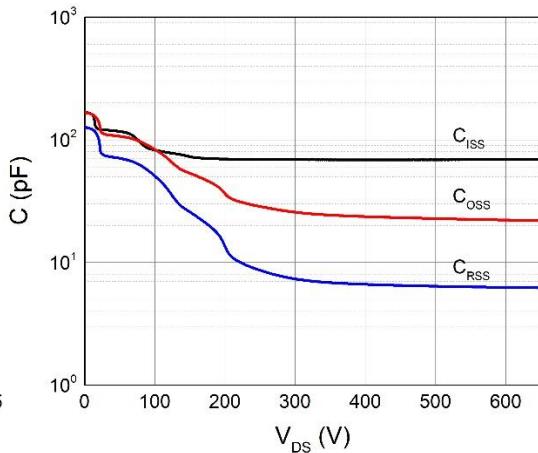
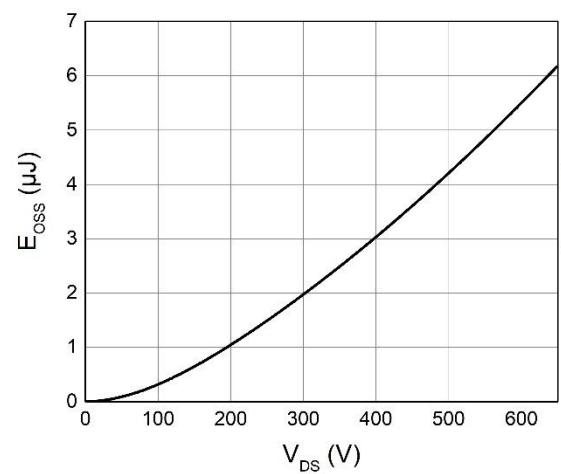
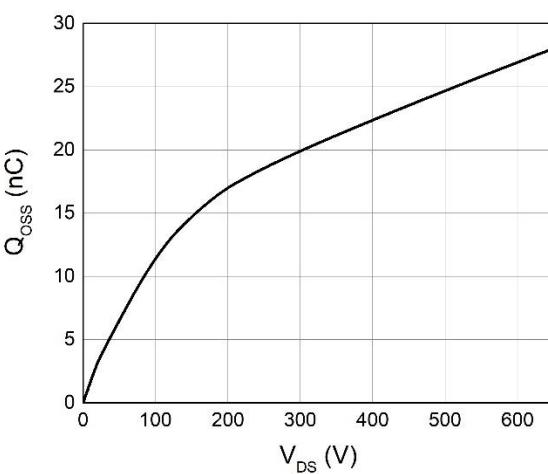


Figure 4. Typical Capacitance

Figure 5. Typical C_{OSS} Stored EnergyFigure 6. Typical Q_{OSS}

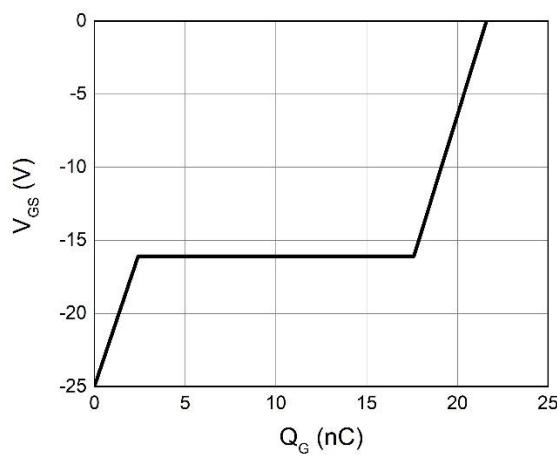


Figure 7. Typical Gate Charge

PACKAGE DIMENSIONS

DFN8x8-4L-A

